

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10733040	NAKAMURA, TAKESHI
	Examiner	Art Unit
	Ensey, Brian	2615

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Discussed with Sinh Tran	1/19/07	BE
Discussed with Paul Harper (AU 2626), Dan Swerdlow (AU 2615) and Walter Briney III (AU 2615)	1/19/07	BE

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner